A Computer-Controlled Integrated Microwave Measurement System in Finline Technique for Automatic Material Parameter Measurements

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Integrated circuit elements in finline technique have been developed for the application in an automatic measurement system which determines the complex material parameters of ferrites and dielectrics. These elements render possible a very fast tuning of the measurement setup in comparison with mechanically controlled systems. They can also be produced much cheaper and more easily than waveguide elements. The design of fully integrated microwave measurement systems in finline technique will be discussed.

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